

Performance of the DAMPE Silicon-Tungsten tracker- converter (STK) during the first 5 years of in-orbit operations

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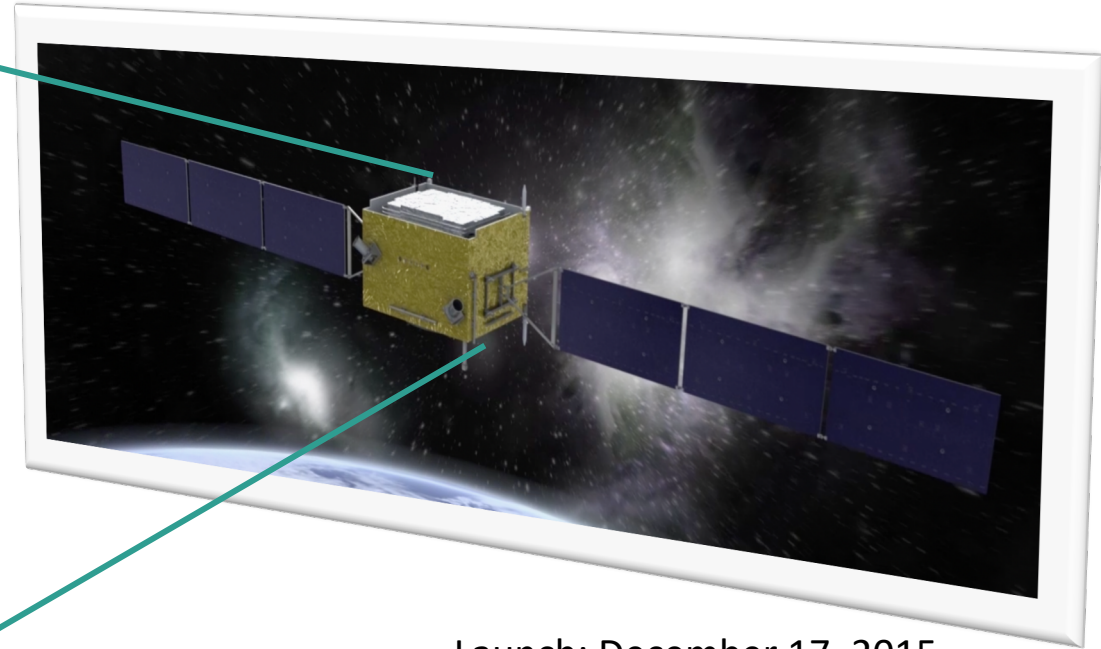
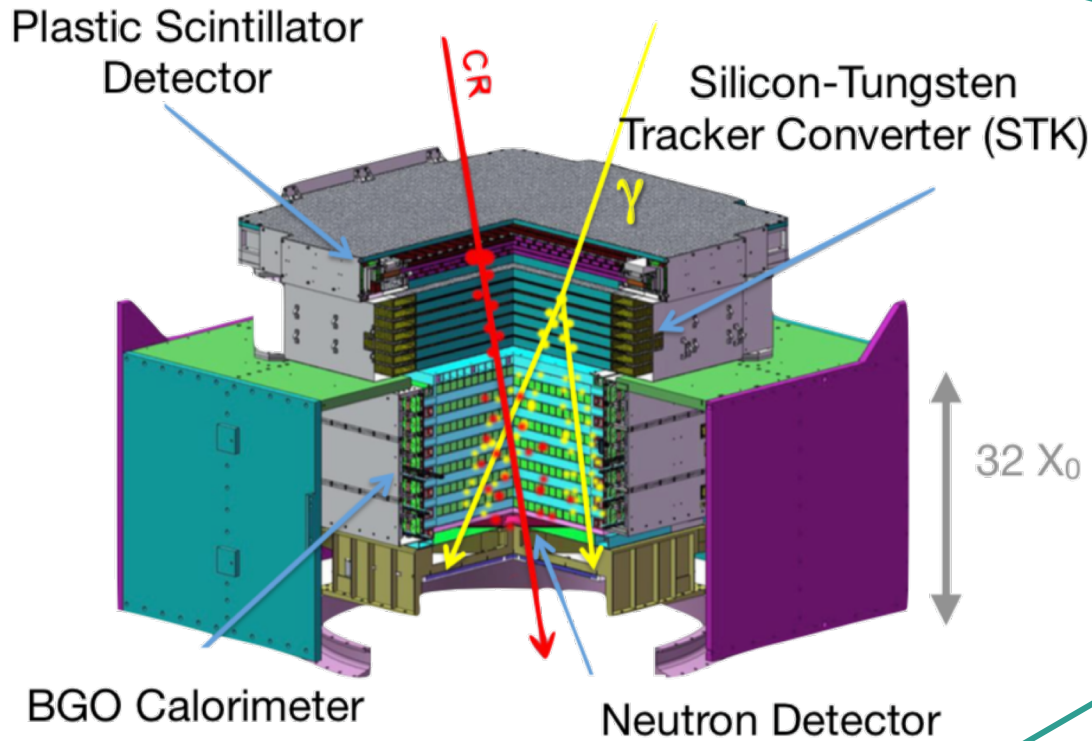
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on behalf of the DAMPE Collaboration



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STK: DAMPE sub-detector



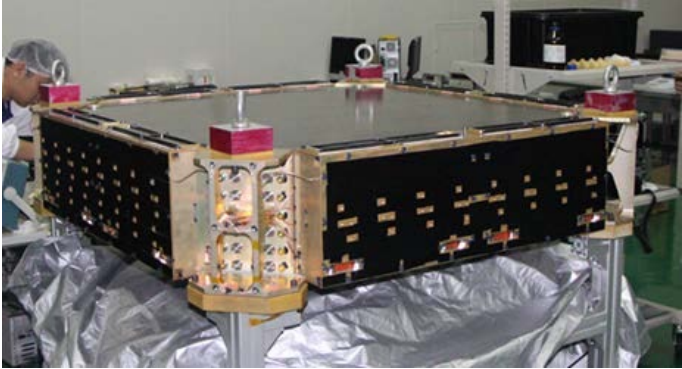
Launch: December 17, 2015

STK tasks:

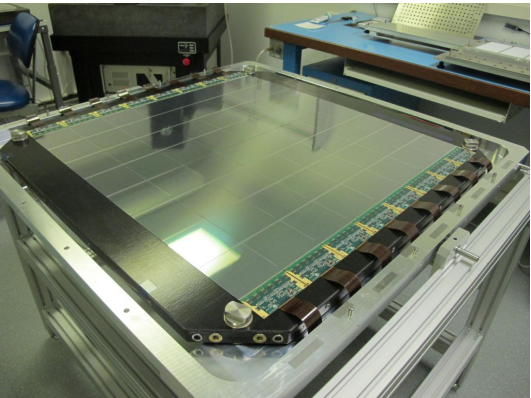
- Track reconstruction
- Charge measurement ($|Z|$)
- Gamma ray conversion ($\gamma \rightarrow e^+ e^-$)

- Outer envelope: 1.12 m x 1.12 m x 25.2 cm
- Detection area: 76 cm x 76 cm
- Total mass: 155 kg
- Total power consumption: 90 W

STK layout



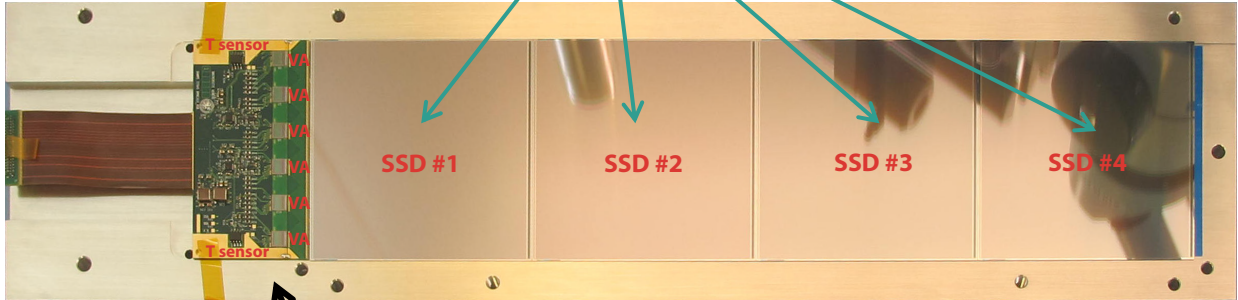
- **12 tracking layers (6x, 6y)** of single-sided silicon strip detectors (SSDs) mounted on 7 support trays.
 - Tray: two carbon fibre sheets with Al honeycomb core
- **1 tungsten layer (1 mm thick)** integrated in the 2nd, 3rd and 4th tray from the top.
 - Total thickness: 0.85 X₀ for photon conversion



1 layer

Si detectors with 768 strips each

1 ladder

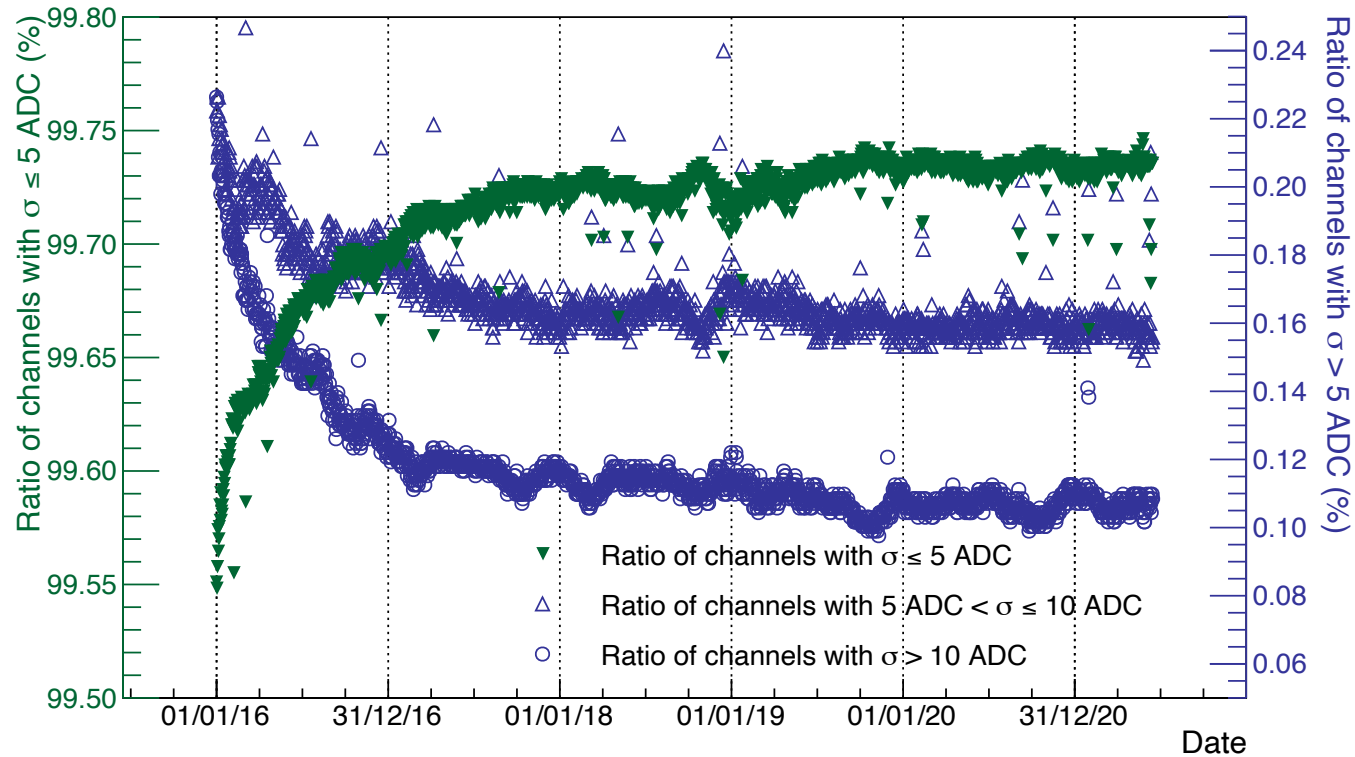


VA140 (front-end chip)

$$16 \frac{\text{ladders}}{\text{layer}} \times 12 \text{ layers} = 192 \text{ ladders}$$

$$\frac{768 \text{ channels}}{2 \text{ ladder}} \times 192 \text{ ladders} = 73'728 \text{ channels}$$

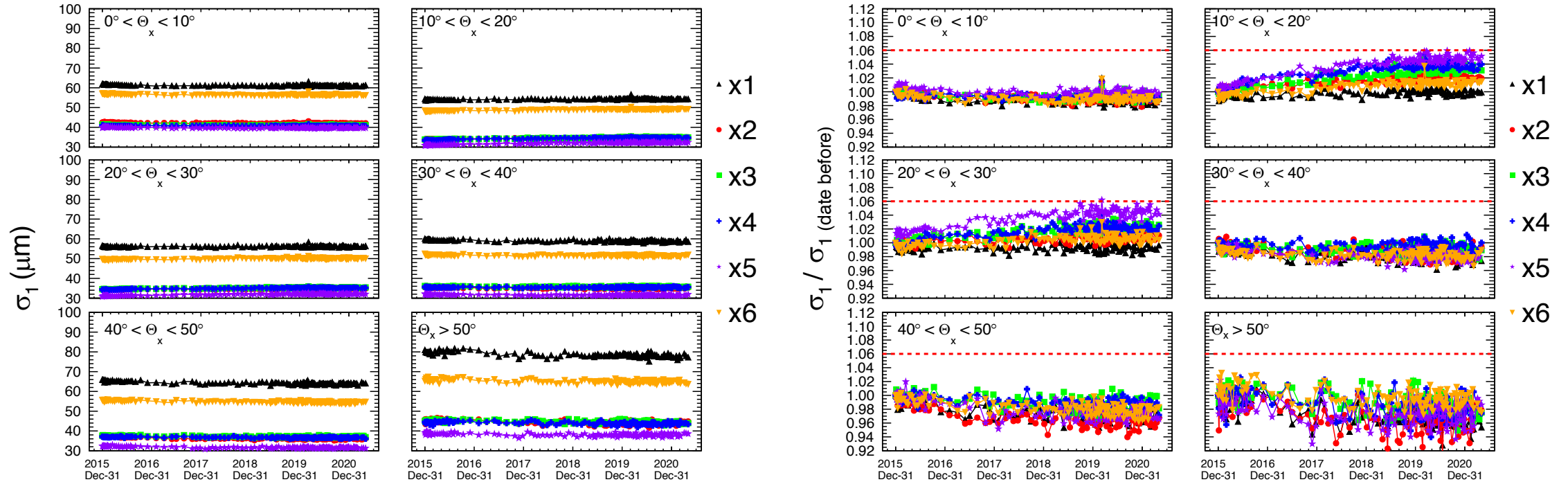
Channel noise time evolution



- Time evolution of the fraction of
1. good channels ($\sigma \leq 5$ ADC);
 2. quite good channels ($5 \text{ ADC} < \sigma \leq 10 \text{ ADC}$);
 3. bad channels ($\sigma > 10 \text{ ADC}$).
- The fraction of good channels increased over time thanks to the stabilization in space and since two years its value is stable around 99.74%.
 - Only 0.11% of the channels are “bad”.

Position resolution evolution

In order to fully exploit the track reconstruction capabilities of the STK, a precise alignment of the instrument is performed once every two weeks.



Thanks to the alignment, the optimal position resolution remains stable and the deviation from the initial values is below 6% for all STK layers and particle incidence angles.